

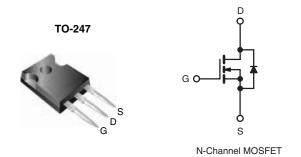
Vishay Siliconix

RoHS

COMPLIANT

Power MOSFET

PRODUCT SUMMARY						
V _{DS} (V)	20	200				
$R_{DS(on)}\left(\Omega\right)$	V _{GS} = 10 V	0.055				
Q _g (Max.) (nC)	23	30				
Q _{gs} (nC)	42					
Q _{gd} (nC)	110					
Configuration	Single					



FEATURES

- Dynamic dV/dt Rating
- · Repetitive Avalanche Rated
- Isolated Central Mounting Hole
- · Fast Switching
- · Ease of Paralleling
- · Simple Drive Requirements
- Lead (Pb)-free Available

DESCRIPTION

Third generation Power MOSFETs from Vishay provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The TO-247 package is preferred for commercial-industrial applications where higher power levels preclude the use of TO-220 devices. The TO-247 is similar but superior to the earlier TO-218 package because of its isolated mouting hole. It also provides greater creepage distance between pins to meet the requirements of most safety specifications.

ORDERING INFORMATION	
Package	TO-247
Lead (Pb)-free	IRFP260PbF
	SiHFP260-E3
SnPb	IRFP260
	SiHFP260

ABSOLUTE MAXIMUM RATINGS T	_C = 25 °C, un	iless otherwi	se noted			
PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V _{DS}	200	V	
Gate-Source Voltage			V_{GS}	± 20		
Continuous Drain Current	V _{GS} at 10 V	T _C = 25 °C	1	46	А	
		T _C = 100 °C	I _D	29		
Pulsed Drain Current ^a			I _{DM}	180	1	
Linear Derating Factor				2.2	W/°C	
Single Pulse Avalanche Energy ^b			E _{AS}	1000	mJ	
Repetitive Avalanche Current ^a			I _{AR}	46	Α	
Repetitive Avalanche Energy ^a			E _{AR}	28	mJ	
Maximum Power Dissipation	T _C = 25 °C		P _D	280	W	
Peak Diode Recovery dV/dtc			dV/dt	5.0	V/ns	
Operating Junction and Storage Temperature Rang	е		T _J , T _{stg}	- 55 to + 150	°C	
Soldering Recommendations (Peak Temperature)	for 10 s			300 ^d		
Mounting Torque	6-32 or M3 screw			10	lbf ⋅ in	
				1.1	N⋅m	

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. V_{DD} = 50 V, starting T_J = 25 °C, L = 708 μ H, R_G = 25 Ω , I_{AS} = 46 A (see fig. 12).
- c. $I_{SD} \le 46$ A, $dI/dt \le 230$ A/ μ s, $V_{DD} \le V_{DS}$, $T_J \le 150$ °C.
- d. 1.6 mm from case.

^{*} Pb containing terminations are not RoHS compliant, exemptions may apply

IRFP260, SiHFP260

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THERMAL RESISTANCE RATINGS				
PARAMETER	SYMBOL	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient	R _{thJA}	-	40	
Case-to-Sink, Flat, Greased Surface	R _{thCS}	0.24	-	°C/W
Maximum Junction-to-Case (Drain)	R _{thJC}	-	0.45	

PARAMETER	SYMBOL	TEST	MIN.	TYP.	MAX.	UNIT	
Static					•	•	
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0$	200	-	-	V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference t	-	0.24	-	V/°C	
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V$	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$		-	4.0	V
Gate-Source Leakage	I _{GSS}	V _G	V _{GS} = ± 20 V		-	± 100	nA
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 20	V _{DS} = 200 V, V _{GS} = 0 V		-	25	μΑ
		V _{DS} = 160 V, V	V _{DS} = 160 V, V _{GS} = 0 V, T _J = 125 °C		-	250	
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 28 A ^b	-	-	0.055	Ω
Forward Transconductance	9 _{fs}	V _{DS} = 5	60 V, I _D = 28 A ^b	24	-	-	S
Dynamic		<u>.</u>					
Input Capacitance	C _{iss}	$V_{GS} = 0 \text{ V},$ $V_{DS} = 25 \text{ V},$ f = 1.0 MHz, see fig. 5		-	5200	-	pF
Output Capacitance	C _{oss}			-	1200	-	
Reverse Transfer Capacitance	C _{rss}			-	310	-	
Total Gate Charge	Qg			-	-	230	
Gate-Source Charge	Q _{gs}	$V_{GS} = 10 \text{ V}$ $I_D = 46 \text{ A}, V_{DS} = 160 \text{ V},$ see fig. 6 and 13 ^b	-	-	42	nC	
Gate-Drain Charge	Q_{gd}	See lig. 0 and 15		-	-		110
Turn-On Delay Time	t _{d(on)}			-	23	-	
Rise Time	t _r	$V_{DD} = 100 \text{ V}, I_D = 46 \text{ A},$ $R_G = 4.3 \ \Omega, \ R_D = 2.1 \ \Omega, \ \text{see fig. } 10^b$		-	120	-	ns
Turn-Off Delay Time	t _{d(off)}			-	100	-	
Fall Time	t _f			-	94	-	
Internal Drain Inductance	L _D	Between lead, 6 mm (0.25") from package and center of die contact		-	5.0	-	- nH
Internal Source Inductance	L _S			-	13	-	
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	Is	MOSFET symbol showing the integral reverse p - n junction diode		-	-	46	- A
Pulsed Diode Forward Current ^a	I _{SM}			-	-	180	
Body Diode Voltage	V_{SD}	$T_J = 25 ^{\circ}\text{C}, \ I_S = 46 \text{A}, \ V_{GS} = 0 \text{V}^{\text{b}}$		-	-	1.8	V
Body Diode Reverse Recovery Time	t _{rr}	T _J = 25 °C, I _F = 46 A, dI/dt = 100 A/μs ^b		-	390	590	ns
Body Diode Reverse Recovery Charge	Q _{rr}			-	4.8	7.2	μС
Forward Turn-On Time	t _{on}	Intrinsic turn	on is dominated by L _S and L _D)				

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. Pulse width \leq 300 μ s; duty cycle \leq 2 %.



TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

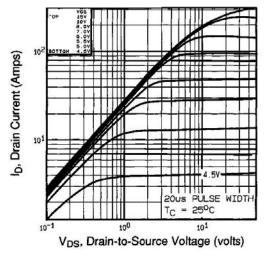


Fig. 1 - Typical Output Characteristics, T_C = 25 °C

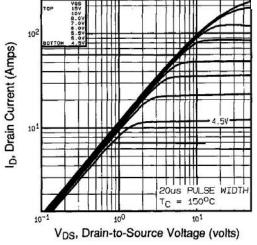
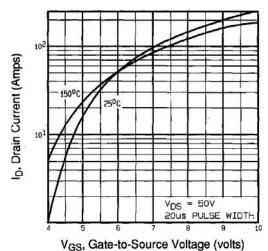
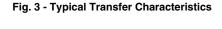


Fig. 2 - Typical Output Characteristics, T_C = 150 °C



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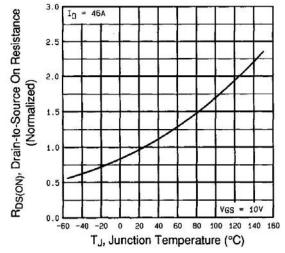


Fig. 4 - Normalized On-Resistance vs. Temperature

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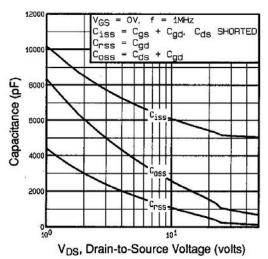


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

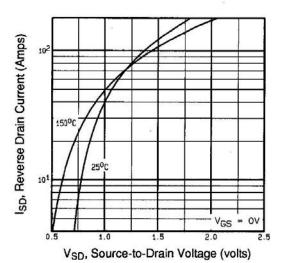


Fig. 7 - Typical Source-Drain Diode Forward Voltage

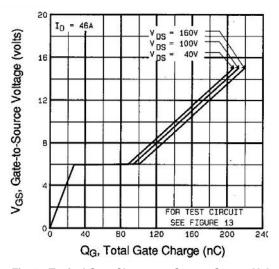


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

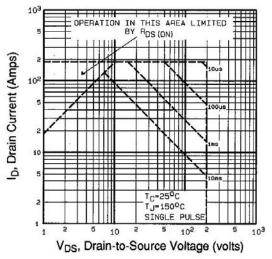


Fig. 8 - Maximum Safe Operating Area





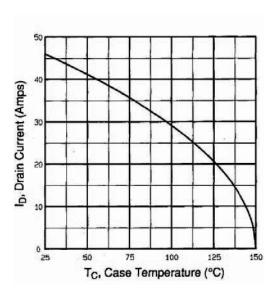


Fig. 9 - Maximum Drain Current vs. Case Temperature

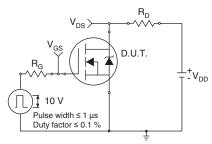


Fig. 10a - Switching Time Test Circuit

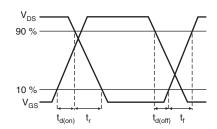


Fig. 10b - Switching Time Waveforms

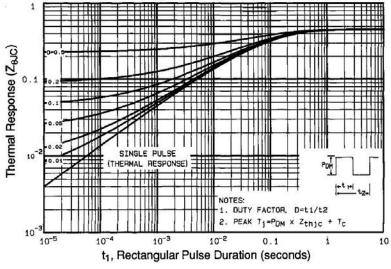


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

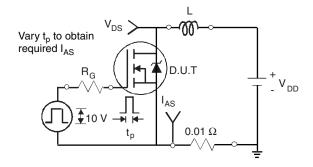


Fig. 12a - Unclamped Inductive Test Circuit

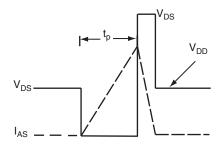


Fig. 12b - Unclamped Inductive Waveforms

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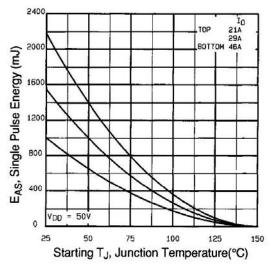


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

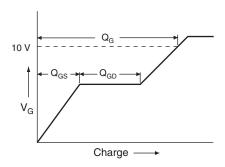


Fig. 13a - Basic Gate Charge Waveform

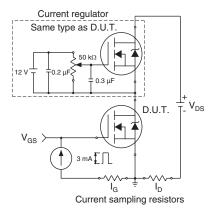
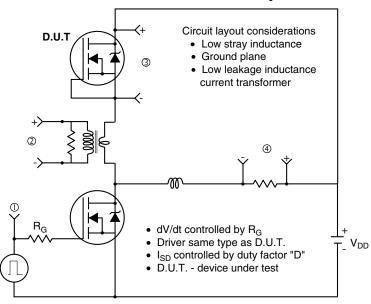
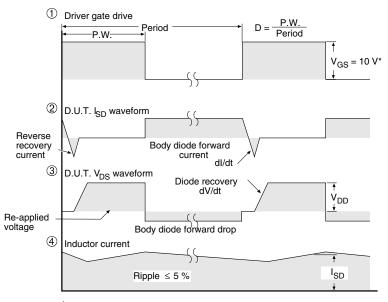


Fig. 13b - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit





* V_{GS} = 5 V for logic level devices

Fig. 14 - For N-Channel

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